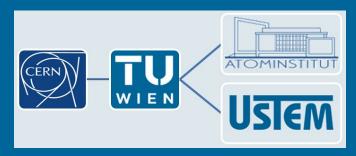


# TU Wien Contribution during FCC Study (2016-2021)

- M. Eisterer Atominstitut / TU Wien
- J. Bernardi USTEM / TU Wien





Low Temperature Physics and Superconductivity



#### Research Projects

Nb<sub>3</sub>Sn Conductor R&D

Beam Screen Development (HTS)

Marie Skodowska-Curie ITN EASITrain







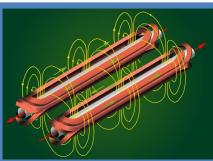












#### Nb<sub>3</sub>Sn Conductor R&D

- 16 T dipole magnets
- 1500 A/mm<sup>2</sup>
- 4.2 K

#### Beam Screen Development (HTS)

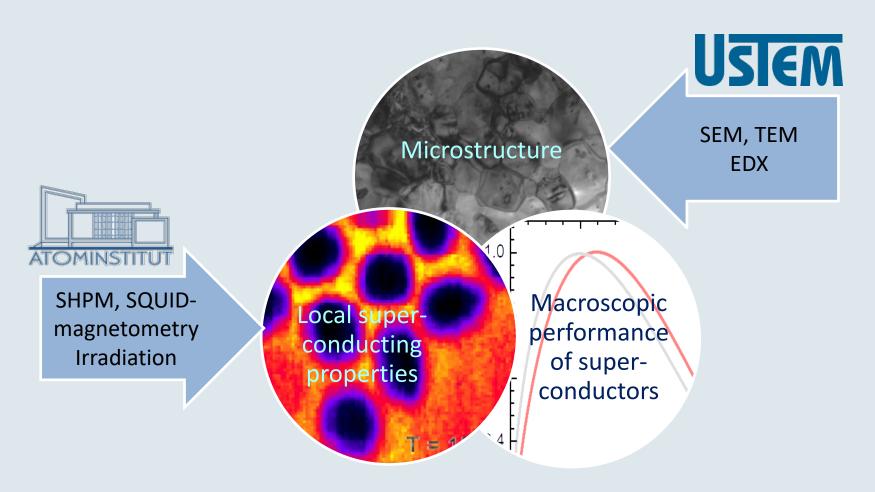
- Low impedance coating for reduction of beaminduced RF image currents
- Operation at 50 K for reduced cryogenic power consumption







### Goal of the investigation







#### Investigations at ATI



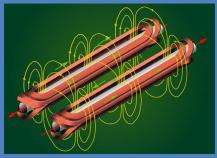
- Measurements of the critical currents
- Irradiation experiments of superconducting materials
- Magnetic field mapping
- Search for material inhomogeneities
- Finding the relationship between microstructure and superconducting properties





## How to achieve $J_c=1500 \text{ A/mm}^2$ ?





#### Nb<sub>3</sub>Sn Conductor R&D

- 16 T dipole magnets
- 1500 A/mm<sup>2</sup>
- 4.2 K

#### Two main concepts:

- Artificial pinning
- Reduction of inhomogeneities





#### Introduction

## Superconducting properties (e.g. $T_C$ , $B_{C2}$ , $J_C$ ) in Nb<sub>3</sub>Sn wires are influenced by:

#### Composition

- Sn:  $Nb_{1-\beta}Sn_{\beta}$
- Additives: Ti, Ta
- $\bullet \rightarrow T_C, B_{C2}$

#### Morphology

- grain size (grain boundaries)
- Defects (APC)
- $\bullet \rightarrow J_C$

## Composition gradients

•  $\rightarrow$  spatial  $T_C$  distribution





#### Irradiation experiments

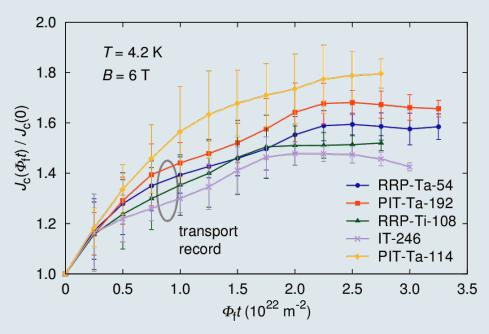


- Irradiation of short wire samples in the TRIGA Mark-II reactor at Atominstitut
- Sequential irradiation in relatively small steps in order to assess fluence dependence of superconducting properties
- Very important also for nuclear fusion





### Irradiation experiments



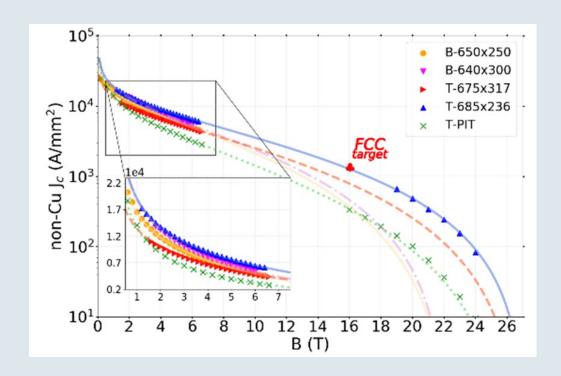
- Critical current density increases significantly in irradiated wires because of nano-sized defects.
- FCC target was obtained in industrial Nb<sub>3</sub>Sn wire!
- Only model system. Later realized by oxide nano-particles in prototype wires.



Baumgartner, T. et al., Sci. Rep. 5, 10236; doi: 10.1038/srep10236 (2015).



#### Artificial pinning centers



- "Addition" of Zr-O nanoparticles
- Collaboration with USA: Ohio State University, Hypertech, Fermilab





### Magnetometry - SHPM

#### Micro Hall Scanner

- Principle:
  - Measurement of local magnetic field, either in applied magnetic field or with remnant magnetization

#### **Experiment**

- Field up to 8 T, range: 3 x 3 mm<sup>2</sup> @ 1 μm
- Goal
  - Evaluating  $T_C$  gradients by scanning in the Meißner state at different temperatures

Scanner head with

mounted sample

• Assessing inhomogeneities in  $J_c$  by inversion of the Biot-Savart law



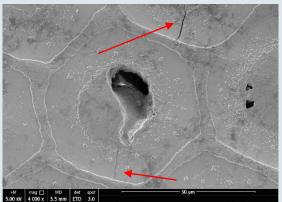


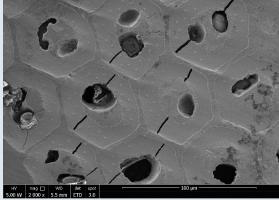
# Sample preparation for Micro Hall Scanner

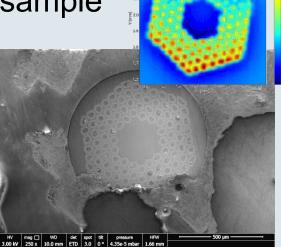
 Thin slice of less than 10 µm prepared by mechanical polishing with diamond disks

Parallel and even surfaces essential

Polishing induces damage on the sample





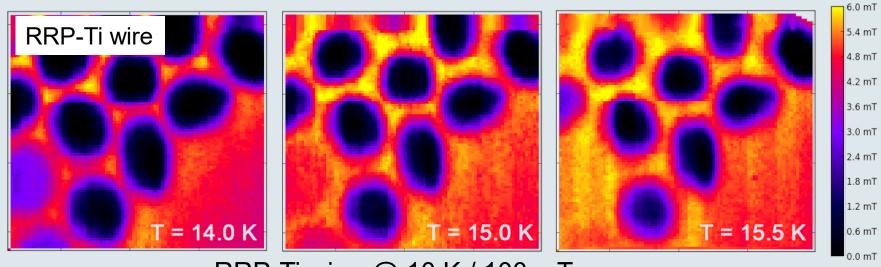








#### Magnetic Inhomogeneities



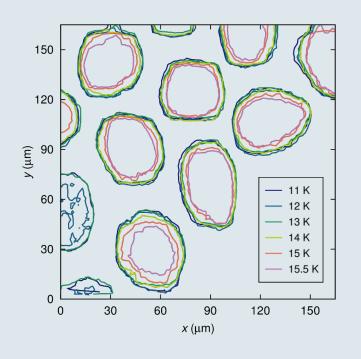
RRP-Ti wire @ 10 K / 100 mT

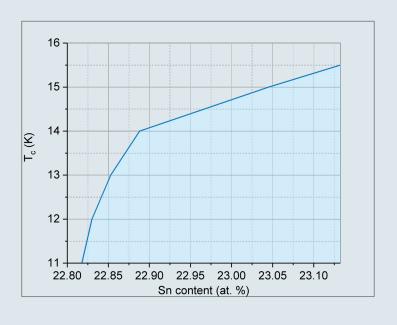
- RRP-Ti wire, scanned in the Meißner state at different temperatures
- Change in screened area reveals  $T_C$  gradient in the sub-elements
- For finding inhomogeneities in  $J_{\mathcal{C}}$ , scans at fields of several Tesla will be performed





#### Meißner scans of RRP-Ti wire





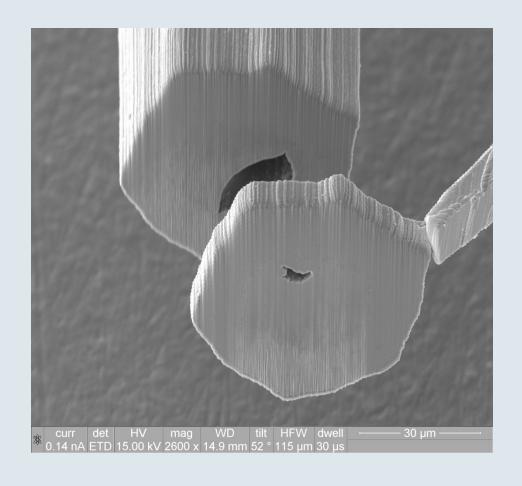
- Meißner Scans on 10 µm thin slice of RRP-Ti wire
- Screening radius depends on temperature due to gradient in Sn content
- Dependency of  $T_C$  from the Sn content
- Small change in Sn content heavily impacts  $T_C$





### Sample Preparation of subelement

Preparing thin slices of etched subelements using FIB for SHPM measurements

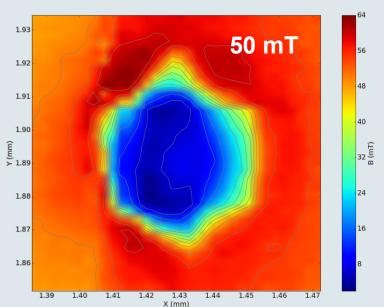


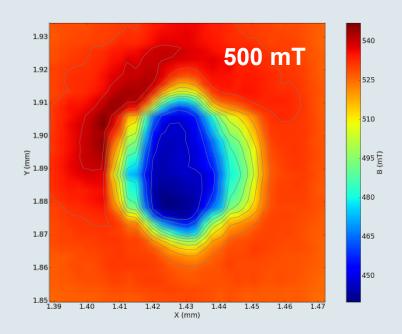




#### Magnetic Inhomogeneities

#### Hall scans of subelement at 5 K



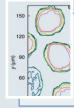


- FIB preparation of individual single subelements is feasible
- For detection of inhomogeneities of  $J_{\mathbb{C}}$  Hall scans at higher applied fields will be performed





## Investigations at USTEM



Composition gradients in Nb<sub>3</sub>Sn wires



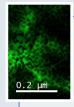
**Irradiation Effects** 



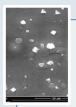
Tl1223 for beam screens



Artificial pinning centers (APC)



Carbon-Cluster in MgB<sub>2</sub>



Coated conductors YBCO



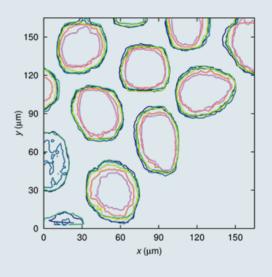


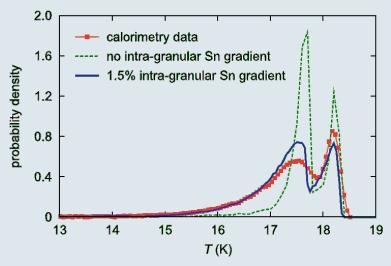






### **Composition Gradients**





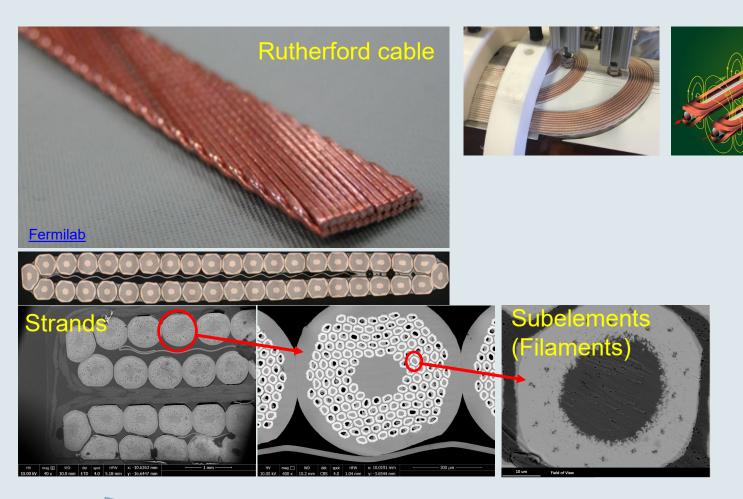
Thomas Baumgartner et al, SUST 30, (2017)

- Magnetometry and calorimetry lead to different distribution functions
- Caused by Sn distribution within individual grains





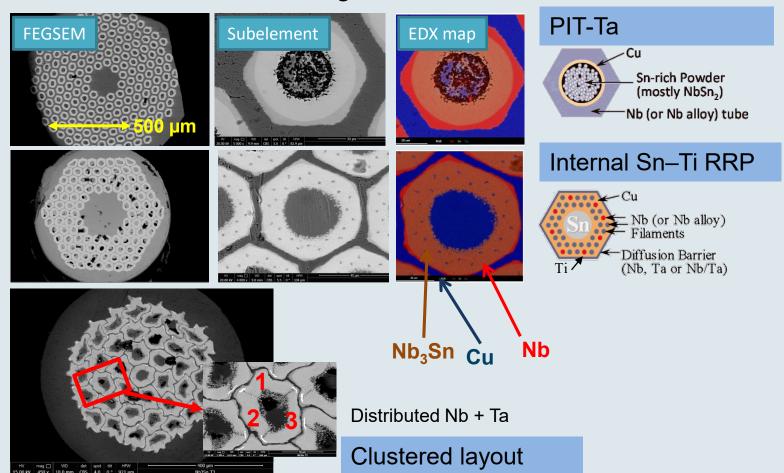
## Nb<sub>3</sub>Sn Conductor R&D







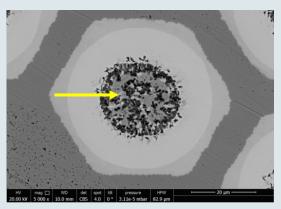
## Investigated Nb<sub>3</sub>Sn wires

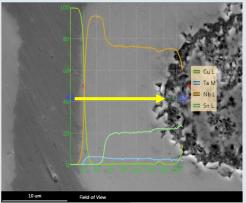


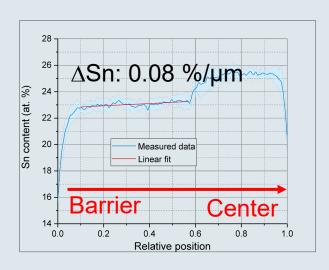


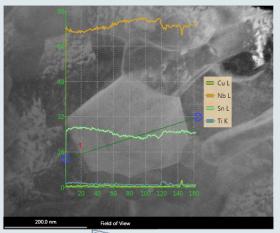


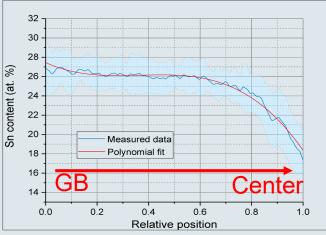
#### Sn distribution within PIT-Ta

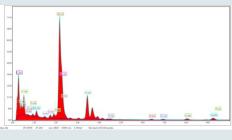














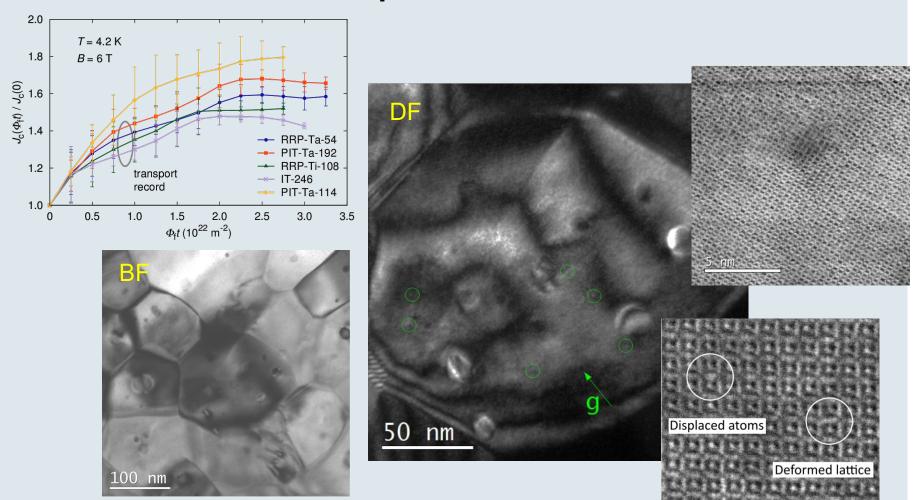


#### Irradiated RRP-Ti wire





## Irradiation experiments





Formation of nanosized defects



#### TI1223 for Beam Screens

Synchrotron radiation must be absorbed at 50 K

- Vacuum requirements
- Cryogenic efficiency
- Power consumption
- Cu is not sufficient
- YBCo or TI based HTS are an option



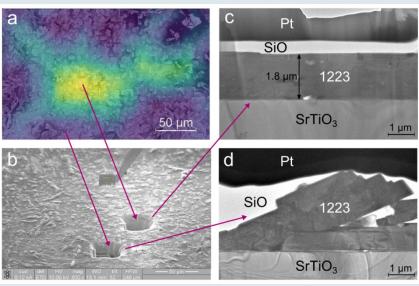
TI-HTS produced at CNR Spin / Genova



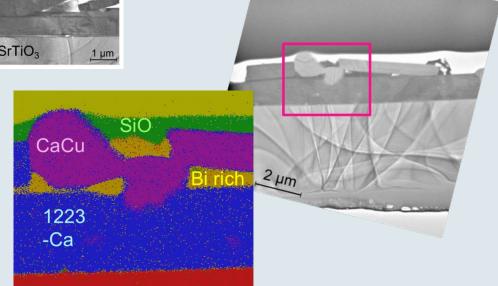




### What influences sc properties



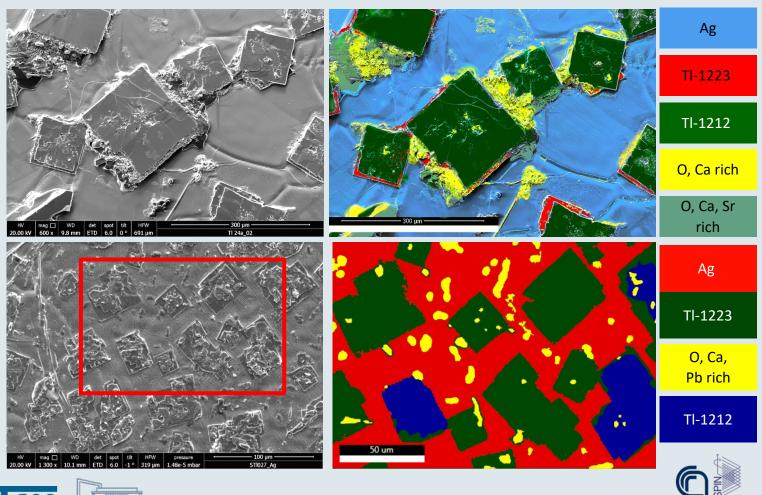
- Misagligned 1223 grains
- Impurities







## Beam Screen Development (HTS)

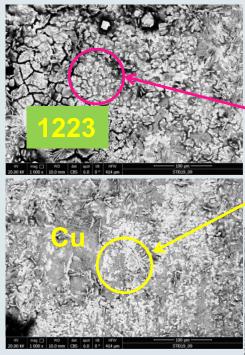


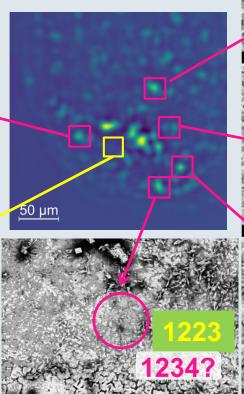


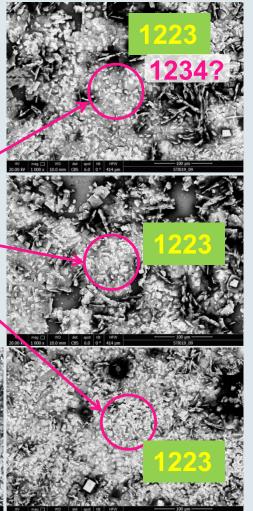


## Beam Screen Development (HTS)

Correlation of sc properties with microstructural features







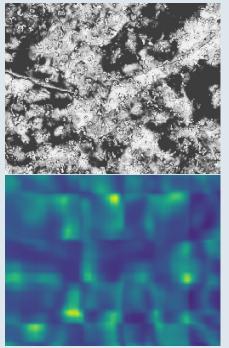


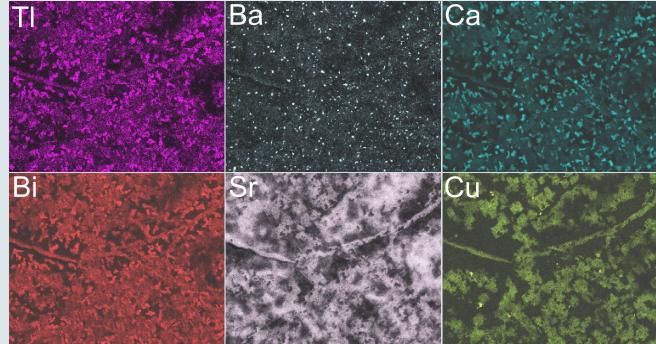




## µHall: Magnetic field mapping

Comparison between remnant magnetic field and local composition of the superconductor









## Nb<sub>3</sub>Sn with artificial pinning

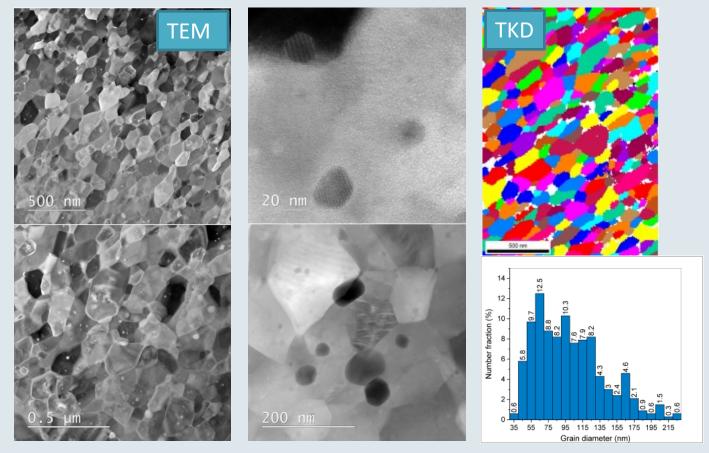
Formation of ZrO<sub>2</sub> or HfO<sub>2</sub> precipitates

- Grain size refinement (more grain boundaries)
- Additional pinning centers





## Nb<sub>3</sub>Sn with APC

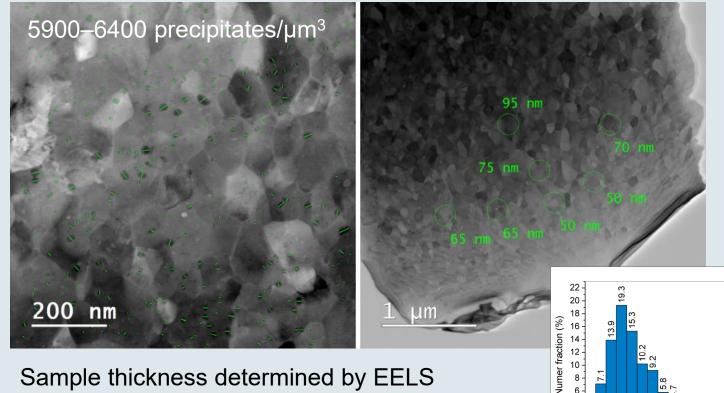




Grain refinement determined by TKD



## Nb<sub>3</sub>Sn with APC



Particle diameter (nm)

Sample thickness determined by EELS Estimation of APC density





### Scientific Output FCC related

2016 - 2021

- 14 Publications in Journals
- 11 Poster Presentations
- 20 Talks
- 3 PhD and 2 PhD



